

## Main Unit Spec

Model Type	KrF (248 nm) DUV Scanner
Wafer Size	300 mm
Resolution	≤ 130 nm
Numerical Aperture (NA)	0.45 ~ 0.70
Reticle Size	6 in. (0.25 in. thick)
Reduction Ratio	3.125:1
Field Size	33 mm x 42.2 mm
Overlay Accuracy	≤ 9 nm ( $ m  + 3\sigma$ )
Footprint (W x D x H)	2,300 mm × 5,155 mm × 2,900 mm
Options	AFIS Illumination System Pellicle Particle Checker SMIF OHT Compatible PC Remote Console Online Functions (GEM2)